

W Production cross section with plug electrons (1.1<|η|<2.8)

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# Why ?

CDF measured W production cross section using e and  $\mu$  in central region Sell known quantity ⇒Excellent to test silicon standalone tracking capability  $\rightarrow$  Measure efficiencies on data, check MC Scheasurement interesting per se (unexplored rapidity region) and ⇒Path to other interesting physics processes (associated production, decays involving Ws etc)



### How

We measure the W production cross section looking for Selectron in the forward region ⇒Em clusters in *Plug* ⇒MET  $\Rightarrow$  Clusters are matched to a 3D track independently reconstructed by the tracking system (i.e. no use of calorimetric info)  $\rightarrow$ Due to the  $\eta$  region this means using mostly silicon (SVXII, ISL) with or without COT  $\rightarrow$  This is very close to what is done in the central region



### Data samples

We use the plug electron dataset collected in the first preshutdown period (March 2002-January 2003), equivalent to about 64 pb<sup>-1</sup> Sequire MET\_PEM trigger fired ⇒Require working plug and silicon ("Good silicon Run" Seconstructed using 4.11.1 In order to measure efficiencies (trigger, ID etc)  $\forall Z \rightarrow ee$  (Central plug) ♥ JETXX (XX=20,50,70)



### Ingredients

The recipe for cross section is always the same:

 $(N_{cand}-N_{back})/(\epsilon \times L)$ 

 $\Rightarrow \varepsilon = \varepsilon_{sele} \times \varepsilon_{trigger}$ 

#### Measure efficiencies and background mostly using data

#### Requirements

 $\Leftrightarrow$  calorimetric

- ⇒EM clusters in plug region (1.1<|η|<2.8) with large E<sub>T</sub>
   ⇒Cluster to be consistent with being an electron and isolated (ID)
   ⇒Large MET
   ☆ tracking
  - ⇒Require a match with a track extrapolated to the PES

⇒Require track to have 0.5<E/p<2



#### Selection

Initial dataset Trigger MET(GeV) ♦ MET\_PEM fired Primary vertex ♥ |PVZ|<60 cm</p> Electron ♦ E<sub>T</sub>>20 GeV ♦ 1.1< |η|<2.8</p> ♥ Electron ID Transverse Cluster Energy vs Missing Et ra  $\Rightarrow$  Had/Fm < 0.05 ⇒Relative Isolation<0.1 MET> 20 GeV Require a track( $P_T$ >1 GeV/c) to match:  $\langle \langle \Delta X \rangle \langle 3 cm \rangle | \Delta Y \rangle \langle 3 cm \rangle$  $\Rightarrow \Delta$  indicates (PES-extrapolated track) ♦ 0.5< E/p < 2</p>

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60

80

ET(GeV)

1.00



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Large Background contamination. Use tracks to clean

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# After track selection

After track matching and E/p cut sample is clean:



#### Top: All, Middle: East, Bottom: West

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### Background

#### QCD background is calculated using the MET vs ISO method.

 $\clubsuit$  Corrections for  $W \rightarrow \tau v$ ,  $W \rightarrow ev, Z \rightarrow ee$  contributing to the different regions are applied.



 $W \rightarrow \tau v$  and  $Z \rightarrow ee$ background are estimated using MC and normalized to candidates

Final result for the three contributions is (statistical uncertainty only):

> ⇒N(QCD)=495 ± 62 ⇒N(Z)=87±13 ⇒N(W→τν)=324±23

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### Acceptances and efficiencies

 $\varepsilon = \varepsilon_{kin} \times \varepsilon_{id} \times \varepsilon_{pvz} \times \varepsilon_{track} \times \varepsilon_{E/p} \times \varepsilon_{trg}$ Geometrical and kinematical acceptance  $\Rightarrow$  ET>20 GeV, 1.1< $|\eta|$ <2.8, MET>20 In red the ones  $\rightarrow$  Computed using MC measured using data **Electron ID efficiency**  $\Rightarrow$  Had/EM<0.05, Isorel<0.1  $\rightarrow$  Measured using Z  $\rightarrow$  ee (CP) Track Matching  $\Rightarrow \Delta X \Delta Y < 3 \text{ cm}$  $\rightarrow$  Measured using plug leg of Z  $\rightarrow$  ee (CP) events E/p requirement ⇒0.5<E/p<2  $\rightarrow$  Measured using plug leg of Z  $\rightarrow$  ee (CP) events PVZ efficiency ⇒ |Z|<60 cm  $\rightarrow$  Measured Z $\rightarrow$ ee (CP), after removal of central leg Trigger efficiency  $\Rightarrow$  MET\_PEM fired

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Measured using EWK MC sample wewk09e processed using V4.9.1/4.11.1 ♦ A = (0.3112±0.07) Systematics: Et Scale ♥ Et Smearing W Pt tuning ♥ U Recoil 🗞 Extra Material ♥ PDF

#### Systematics summary

Source	∆ Acc/Acc (%)
Et scale	0.35
Et smer	0.16
Extra material	0.90
Pt tuning	0.06
U recoil	0.35
PDF	+1.71-1.37
Total	+2.00-1.72



#### Some systematics (material, PDF)

Extra material, use standard EWK MC dataset

♦ Change central (+-1.5% X<sub>0</sub> of Cu)

#### ⇒Negligible

♦ Change by +/-1/6 X<sub>0</sub> Fe in plug (0.84, 0.90)%, take the biggest 1.5 M events generated for each PDF error eigenvalue, formula agreed within the Ewk..



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### $Z \rightarrow ee$ , CP data sample

# Central leg (tight) Plug leg: ♦ |PVZ|<60</p> ♦ ET>20, 1.1<|η|<2.8</p> ♦ Had/Em<0.125</p> ♦ 80<Mee<100</p>

Used to measure  $\Rightarrow \varepsilon$  ID efficiency  $\Rightarrow 0.961 \pm 0.0037 \pm 0.022$   $\Rightarrow$  track matching efficiency  $\Rightarrow \Delta X, \Delta Y$  $\Rightarrow E/p$ 



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### **Track matching**

3D track found by tracking algorithm is extrapolated to PES location: Correction for PES misalignment is applied, however (small) residual misalignment... checked that no effect on candidates





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### Scale Factor (SF)

We might also define ε<sub>tracking</sub> as:
Setracking<sup>=</sup> ε<sub>tracking</sub>(W<sub>MC</sub>)× SF where SF:
SF = ε<sub>tracking</sub>(Z<sub>data</sub>)×ε<sub>tracking</sub>(Z<sub>MC</sub>)
Sys obtained by assuming SF flat or taken as a function of η,φ and E<sub>T</sub>. Biggest effect due to E<sub>T</sub>, taken as syst.



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### SF and Tracking







#### SF as a function of $\eta$



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### E/p requirement

We apply a cut to E/p : 0.5<E/p<2



As MC does not model the distribution well, we measure the efficiency on  $Z \rightarrow ee$  sample



ε= 0.639±0.015(stat)±0.01(syst)

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## **PVZ efficiency**

Primary vertex finding efficiency is measured using  $Z \rightarrow ee$  (CP) events.

- Sevents are selected and then the central leg is stripped away
  - ⇒Sample is reprocessed (now it looks W-plug-like...)
  - ⇒Efficiency is defined as:
  - (# events w/o central leg with |PVZ|<60 cm)

(# events w central leg and central trk  $|Z_0| < 60$ )  $\epsilon$ = 0.9207±0.0051±0.0035



### **Trigger efficiencies**

Trigger MET\_PEM: ♥ L1\_EM8\_MET15 ⇒L2\_PEM20\_MET15 →L3\_PEM20\_MET15 Using backup triggers we find an overall:  $\epsilon_{trig} = 0.958 \pm 0.012$ We checked with **JET20, JET50, JET70** (agreement)

 $\Rightarrow$  Side effect: we measured the trigger  $\epsilon$  also in the other data taking periods..







#### **Cross Section**

N.candidate events	10461	
N.background QCD events	$495 \pm 62 \text{ (stat)}$	$\pm 247 \text{ (sys)}$
N.background Z events	$87 \pm 13$ (stat)	
N.background $W \rightarrow \tau \nu$ events	$324 \pm 23$ (stat)	
$Lumin.(pb^{-1})$	64	$\pm 4.3$ (sys)
$\epsilon$	$0.052 \pm 0.002$ (stat)	$\pm 0.002 \text{ (sys)}$

	Value		Syst.error
$\epsilon_{Kin}$	$0.3112 \pm 0.0007$		0.0058
$\epsilon_{Pvz,Kin}$			0.0035
$\epsilon_{PVZ}$	$0.92\pm0.005$		
$\epsilon_{ID}$	$0.961 \pm 0.004$		0.022
$\epsilon_{trig}$	$0.958 \pm 0.011$		
$\epsilon_{E/p}$	$0.64 \pm 0.015$		0.001
ε		$0.170\pm0.005$	0.005
$\epsilon_{tracking}$		$0.322\pm0.009$	0.006
$\epsilon_{Lum}$		$0.951 \pm 0.001$	0.005
Overall $\epsilon$		$0.052\pm0.002$	0.002

#### σ =2.874±0.034(stat)±0.167(syst)±0.172(lum) nb

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#### Conclusion

Added one point to a 20 years old history...more to come

#### Work in progress:

5.3.1: increase tracking efficiency, increase in candidates...



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### 5.3.1...Very preliminary

Candidates... (plug e)

### Tracking efficiency in $Z \rightarrow ee (CP)$ : 0.48±0.01



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# $\eta$ dependence of tracking eff.



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#### $\varphi$ and $\eta$ dependence



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### Background

#### QCD background is calculated using the MET vs ISO method:



Corrections for  $W \rightarrow \tau v$ ,  $W \rightarrow ev, Z \rightarrow ee$  to the different regions are applied.  $\Rightarrow$  Final background :  $\Rightarrow N(QCD)=495 \pm 62$  $\Rightarrow N(Z)=87\pm13$ 

⇒N(W→τν)=324±23



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#### Z->ee CP sample



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## $Z \rightarrow ee (CP) sample$

#### A sample of Zee is selected

♦ Central leg (tight)
 ♦ Plug leg
 ⇒ |PVZ|<60</li>
 ⇒ ET>20, 1.1<|h|<2.8</li>
 ⇒ Had/Em<0.125</li>
 ⇒ 80<Mee<100</li>



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CII

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E/p Study- Z->eeCP

Invariant mass Mee divided in E/P regions: 0<E/p<0.5 0.5<E/p<2



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	E/p selection				
Background contamination is calculated with Fake Rate method (G. Veramendi and A. Robson A <sub>FB</sub> and Z→ee CP Xsec)					
Eff E/P =					
After Trk Match	All 932	East 510	Bkg East 1.2 +/-1	West 423	Bkg West 1.0 +/-1
After 0.5 <e p<2.0<="" td=""><td>596</td><td>325</td><td>~0 +/-1</td><td>271</td><td>~0 +/-1</td></e>	596	325	~0 +/-1	271	~0 +/-1



## Et scale and smearing

 $\Delta Acceptance = (Default - (\pm 3\sigma))$  $\delta = (\Delta Acceptance / Acceptance) (\%)$ 

Scaling 2.5%

Smearing 2.7%

Description	-3	Α	A/A (%)	+3	ΔA	A/A (%)
Et Scaling	1.90%	0.0011	0.35	3.10%	0.0010	0.32
Et Smearing	1.60%	0.0005	0.16	3.80%	0.0005	0.16
Total scaling	0.35			MAX	(δδ.	_)
Total smearing	0.16				· +3031	Υ.

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# Pt tuning in Pythia

As in W $\rightarrow$ enu central:

 $d\sigma/dp_T$  of ee pairs in 66 $< M_{ee} < 116$  tuned by four

Pythia parameters

Comparison with CDF Run I data

 $\Delta$ Acceptance = (Default - ( $\pm 3\sigma$ ))

 $\delta = (\Delta Acceptance / Acceptance) (\%)$ 

Parameter	MAX( $\delta_{+3\sigma}, \delta_{-3\sigma}$ )
Par 62	.01
Par 64	.04
Par 91	.04
Par 93	.00
Total	0.057

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## Extra Material

 $\Delta Acceptance = (Default - (\pm 3\sigma))$ 

 $\delta = (\Delta Acceptance / Acceptance) (\%)$ 

MC datase	t Description	∆Acceptance	(%)
Wewk4e	Extra -1.5% Xo Cu in centra	1 0.00003	-
Wewk3e	Extra +1.5% Xo Cu in centra	al 0.00002	-
Total	MAX( $\delta_{+\lambda}, \delta_{-\lambda}$ )		_

### Negligible contribution from Central extra material

MC dataset	Description	<b>A</b> Acceptance	δ(%)
Wewk6e	Extra -1/6 Xo Fe in plug	0.0028	0.90
Wewkae	Extra +1/6 Xo Fe in plug	0.0026	0.84
Total	MAX( $\delta_{+3\sigma}, \delta_{-3\sigma}$ )		0.90
			Systematics for extra material

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### Recoil energy Perp & Par



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Recoil energy

$$\overrightarrow{U} = -(\overleftarrow{E}_{T} + \overrightarrow{E}_{T}) \longrightarrow U_{\perp} & U_{II} \longrightarrow$$

Parallel and perpendicular difined with respect of lepton direction

• Data and MC for different values of parameters were compared using  $\chi^2$  distributions

• Value of parameter for  $\chi^2_{min}$ used to recalculate Met and acceptance • Appropriate values of parameters of  $3\sigma$  shift in  $\chi^2$  used for systematics study

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$$U'_{||} = K_{||}(U_{||} + C_{||})$$
$$U'_{\perp} = K_{\perp}(U_{\perp} + C_{\gamma})$$
$$U' = K^* \text{sqrt}(U^2_{\perp} + U^2_{||})$$



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### Recoil energy table

$$U'_{II} = K_{II} (U_{II} + C_{II})$$
$$U'_{\perp} = K_{\perp} (U_{\perp} + C_{\perp})$$

	K <sub>II</sub>	$\mathrm{K}_{\perp}$	K	C <sub>II</sub>	$C_{\perp}$
n.d.f.	200	200	200	200	200
Fit value	1.097	1.104	1.069	-0.465	0.006
∆valu <u>ę</u>	0.034	0.037	0.027	0.153	0.151
$\Delta A_{+3\sigma}$ (%) ( $\Delta A/A$ )	-	I	0.18	0.29	0.004
$\Delta A_{-3\sigma}$ (%) ( $\Delta A/A$ )	-	Ι	0.17	0.3	0.005
Total $\Delta A/A$ (%)	0.3	5	-		

 $Total = sqrt(0.18^2 + 0.3^2 + 0.005^2)$ 

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### Scale Factor: W vs Z



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### **Track Matching- Wenu**



Plug East Misalignement of ~0.7cm Marginal impact since PES doesn't seed any track. Just matching with 3cm window



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### **Track Matching**



Tracks found by the different tracking algorithms

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E/P Study- W->ev

#### Tracks from W->enu sample



Region in O<E/P< 0.5 coming from very High Pt tracks

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### E/p: signal and back..

Signal sample

#### QCD enriched:







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Q: plot phi vs Z distributions for each layer to confirm that the eta dependence of the scale factor is determined by the differences between the real and the simulated acceptances

- •Look at DAQ status for all Si Ladders in our sample
- •Compare to realistic MC (Run 151435)
- •Study each individual layer
- •Produce a Summary plot







## Silicon Coverage(2) Data/MC

### DATA/MC after Data and MC independently normalized.



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# Track Quality(COT Hits)



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### **PVZ Distributions**

After all cuts



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### PV Vertex and TrkzO

On W $\rightarrow$ ve candidates (after E/P cut)

On Z \rightarrow ee CP Candidates with stripped central track



Difference between TrkzO of plug track – Pvz from ZvertexColl Difference between TrkzO of central electron and PV from Zvertex Coll in Z→ee CP sample with stripped central track





## **Trigger Efficiencies**

Preshut	Tot	East	West
L1_MET15	99.6+/-0.2	100+/-0.2	99.1+/-0.4
L3_MET15	99.9+/-0.1	100+/-0.2	99.8+/-0.3
L1_&_L3_MET15	99.5+/-0.3	100+/-0.2	99.6+/-0.2
L1_MET15 x L3_MI	E <b>199</b> 55+/-0.3	100+/-0.2	99.6+/-0.2
L2_PEM20	96.3+/-1.1	95.1+/-1.4	97.8+/-1.5
Overall	95.8+/-1.2	95.1+/-1.8	96.8+/-1.5

Systematics obtained after shifting Et Eele by +/-1-sigma

```
(+/-3.1,3.6%) +/-1.0%
```

Systematics obtained relaxing the E/P cut:

+/-1.8%

To be conservative we take as systematics the largest uncertainty

We also checked on different sample (JET20) our results and it agrees well within the (large) statistical error.

Eff Trigger (%) =95.8+/-1.2 (stat) +/- 1.8 (syst)  
$$63$$

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Preshut	Tot	East	West
L1_MET15	99.6+/-0.2	100+/-0.2	99.1+/-0.4
L3_MET15	99.9+/-0.1	100+/-0.2	99.8+/-0.3
L1_&_L3_MET15	99.5+/-0.3	100+/-0.2	99.6+/-0.2
L1_MET15 x L3_MI	=19955+/-0.3	100+/-0.2	99.6+/-0.2
L2_PEM20	96.3+/-1.1	95.1+/-1.4	97.8+/-1.5
Overall	95.8+/-1.2	95.1+/-1.8	96.8+/-1.5

Systematics obtained after shifting Et Eele by +/-1-sigma

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(+/-3.1,3.6%) +/-1.0%
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Systematics obtained relaxing the E/P cut:

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<b>Trigger</b> E	ffici	encies
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Preshut	Tot	East	West
L1_MET15	99.6+/-0.2	100+/-0.2	99.1+/-0.4
L3_MET15	99.9+/-0.1	100+/-0.2	99.8+/-0.3
L1_&_L3_MET15	99.5+/-0.3	100+/-0.2	99.6+/-0.2
L1_MET15 x L3_ME	19955+/-0.3	100+/-0.2	99.6+/-0.2
L2_PEM20	96.3+/-1.1	95.1+/-1.4	97.8+/-1.5
Overall	95.8+/-1.2	95.1+/-1.8	96.8+/-1.5

Systematics obtained after shifting Et elec by  $\pm 1 \sigma$ ( $\pm 3.1, \pm 3.6\%$ ) +/-1.0% Systematics obtained relaxing the E/P cut:  $\pm 1.8\%$ To be conservative we take as systematics the largest variation

We also checked on different sample (JET20) our results and it agrees well within the (large) statistical error.

Eff Trigger (%) =95.8+/-1.2 (stat) +/- 1.8 (syst)



# MET\_PEM Trigger: Method

Three periods: Preshutdown Data (Mar2002-Jan2003) Post 1 (Feb 2003-May2003)  $\rightarrow$  PhyTab 1\_04\_\* Post 2 (20 May 2003-Sept 2003)  $\rightarrow$  Phy\_Tab 1\_05\_\*

Turn-On Curves fitted by 2 different curves:

■1/(1+exp(-beta(x-alpha)))

■1-p0 exp(-p1 x)

Will consider x as Raw (offline) variables (MET and Et )



## Trigger Plots: L1 MET15





## L1 MET15 vs Run



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### **L1 MET15**

#### Trigger Eff for the three periods.



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### L3 MET15 vs Run






## L1\_MET15\_&\_L3 MET15



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## L2\_PEM20 vs Run



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JET20 and L3\_PEM20 Performed the same exercise on independent sample: JET20(only preshutdown) Can evaluate overall MET\_PEM efficiency MET PEM Eff(MET PEM)= JET20 and offline selection Total WEST EAST Eff(MET\_PEM)<sub>IET20</sub> 84 2+/-9 4 78 + / -1690 + / 13Evaluated L3\_PEM20 from Z->ee (CP) All events fired PLUG\_ELECTRON\_20 trigger bit  $\rightarrow$ Eff(L3\_PEM20)=100%

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## **Trigger Efficiencies**

Preshut	Tot	East	West	
L1_MET15	99.6+/-0.2	100+/-0.2	99.1+/-0.4	
L3_MET15	99.9+/-0.1	100+/-0.2	99.8+/-0.3	
L1_&_L3_MET15	99.5+/-0.3	100+/-0.2	99.6+/-0.2	
L1_MET15xL3_MET	15 99.5+/-0.3	100+/-0.2	99.6+/-0.2	DraChut
L2_PEM20	96.3+/-1.1	95.1+/-1.4	97.8+/-1.5	PreSnut
Overall	95.8+/-1.2	95.1+/-1.8	96.8+/-1.5	
L1_MET15	99.7+/-0.2	99.8+/-0.3	99.7+/-0.4	
L3_MET15	100+/-0.1	100+/-0.2	100+/-0.3	
L1_&_L3_MET15	99.7+/-0.2	99.8+/-0.3	99.7+/-0.4	
L1_MET15xL3_MET	15 99.7+/-0.2	99.8+/-0.3	99.7+/-0.4	
L2_PEM20	97.4+/-1.4	97.4+/-2.1	97.4+/-2.1	Post1
Overall	97.2+/-1.4	97.2+/-2.2	97.1+/-2.2	1 0311
L1_MET15	99.2+/-0.3	98.6+/-0.6	99.8+/-0.3	
L3_MET15	99.9+/-0.1	99.8+/-0.3	99.8+/-0.3	
L1_&_L3_MET15	99.1+/-0.3	98.4+/-0.6	99.8+/-0.3	
L1_MET15xL3_MET	15 99.1+/-0.3	98.4+/-0.6	99.8+/-0.3	
L2_PEM20	96.1+/-1.4	93.5+/-2.6	98.2+/-1.5	Post?
Overall	95.2+/-1.5	92.1+/-2.7	98.0+/-1.6	1 0312

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